Applicant(s)/Patent Under Application/Control No. Reexamination 10/042,153 SAIKATSU ET AL. Notice of References Cited **Art Unit** Examiner Page 1 of 1 1714 Katarzyna Wyrozebski Lee **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name MM-YYYY Country Code-Number-Kind Code 523/155 Nakamura et al. 07-2003 US-6,596,789 Α 523/156 Yamane, Takeshi 09-2002 US-6,451,872 В С US-US-D US-Ε F US-US-G US-Н US-US-US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Date Document Number Classification Name Country MM-YYYY Country Code-Number-Kind Code Ν 0 Ρ Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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